

N-Channel Enhancement Mode MOSFET

Feature

- 40V/253A
 R_{DS(ON)}=1.5 mΩ (typ.) @VGS = 10V
- 100% Avalanche Tested
- Reliable and Rugged
- Lead-Free and Green Devices Available (RoHS Compliant)

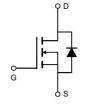
Pin Description



TO-263-2L

Applications

- Switching application
- Li-battery protection



N-Channel MOSFET

Ordering and Marking Information



Package Code

B: TO-263-2L

Date Code XYMXXXXXX

Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)		,	
VDSS	Drain-Source Voltage		40	V
Vgss	Gate-Source Voltage		±20	V
TJ	Junction Temperature Range		-55 to 175	°C
Тѕтс	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode)	Tc=25°C	253	Α
Mounted on	Large Heat Sink		'	
lом	Pulsed Drain Current *	Tc=25°C	1000**	А
	Continuous Danie Comment	Tc=25°C	253	А
lσ	Continuous Drain Current	Tc=100°C	179	А
	M	Tc=25°C	230	W
Pb	Maximum Power Dissipation Tc=100°C		115	W
R_{θ} JC	Thermal Resistance, Junction-to-Case		0.65	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		62.5	°C/W
Eas	Single Pulsed-Avalanche Energy ***	L=0.3mH	1586**	mJ

Note: * Repetitive rating; pulse width limited by max.junction temperature.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

0	D	Test Conditions		HYG013N04NA1			
Symbol	Parameter			Min	Тур.	Max	Unit
Static Cha	racteristics			•			
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} = 2	250µA	40	-	-	V
	V _{DS} =40V,V _{GS}	V _{DS} =40V,V _{GS} =0V		-	1	μA	
Ibss	Drain-to-Source Leakage Current		TJ=125°C	-	-	50	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} = 250μA		2	2.8	4	V
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$		-	-	±100	nA
RDS(ON)	Drain-Source On-State Resistance	V _{GS} = 10V,I _{DS} = 60A		-	1.5	1.8	mΩ
Diode Cha	racteristics	•					
VsD	Diode Forward Voltage	IsD=60A,VGS=0V		-	0.85	1.2	V
trr	Reverse Recovery Time	1 -COA -11 (-14-400A)		-	41	-	ns
Qrr	Reverse Recovery Charge	Isp=60A,dIsp/dt=100A/µs		_	39	-	nC

^{**} Surface mounted on 1in2 FR-4 board.

^{***} Limited by T_Jmax , starting T_J=25°C, L = 0.3mH, R_G= 25Ω , V_GS =10V.

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Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Cumbal	Dovometer	Toot Conditions	HY	HYG013N04NA1		
Symbol	Parameter Test Conditions		Min	Тур.	Max	Unit
Dynamic	Dynamic Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	-	2.3	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	11620	-	
Coss	Output Capacitance	V _{DS} = 25V,	-	1502	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	1050	-	
td(ON)	Turn-on Delay Time		-	38	-	
Tr	Turn-on Rise Time	V _{DD} = 20V,R _G =4Ω,	-	225	-	
td(OFF)	Turn-off Delay Time	IDS=60A,VGS= 10V	-	168	-	ns
Tf	Turn-off Fall Time		-	147	-	
Gate Cha	Gate Charge Characteristics					
Qg	Total Gate Charge	\/ - 22\/ \/ - 10\/	-	265	-	
Qgs	Gate-Source Charge	$V_{DS} = 32V, V_{GS} = 10V,$	-	55	-	nC
Qgd	Gate-Drain Charge	— I _{DS} = 60A	-	94	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

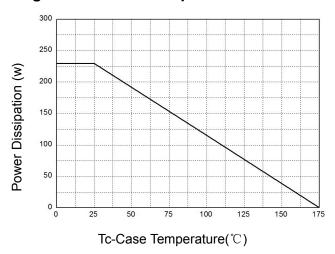
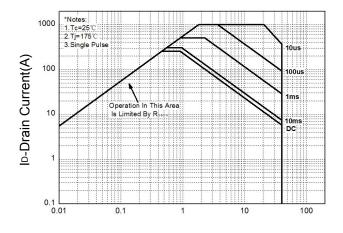


Figure 3: Safe Operation Area



Vps-Drain-Source Voltage(V)

Figure 5: Output Characteristics

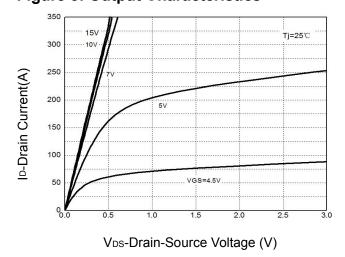
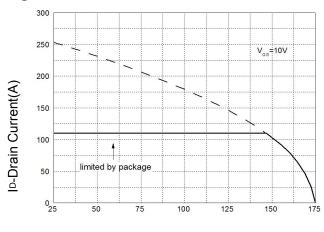
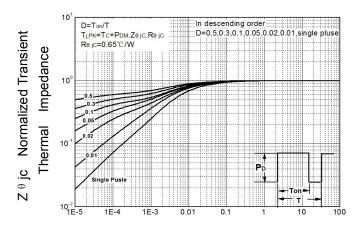


Figure 2: Drain Current



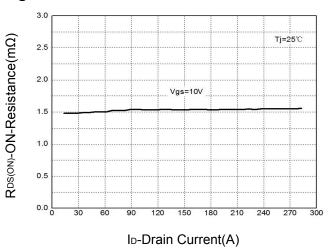
Tc-Case Temperature(°C)

Figure 4: Thermal Transient Impedance



Maximum Effective Transient Thermal Impedance, Junction-to-Case

Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

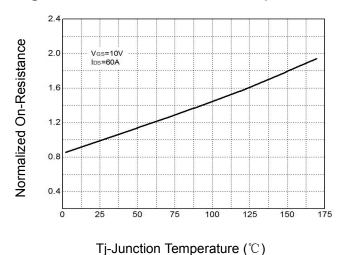
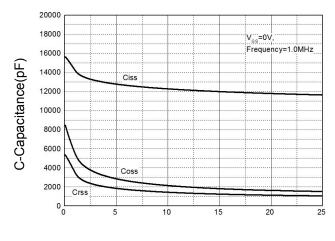
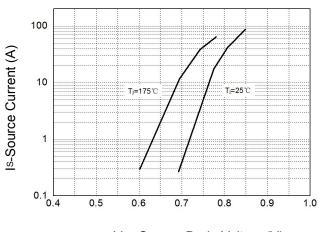


Figure 9: Capacitance Characteristics



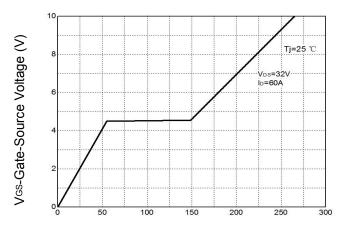
V_{DS}-Drain-Source Voltage (V)

Figure 8: Source-Drain Diode Forward



Vsp-Source-Drain Voltage(V)

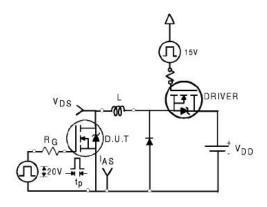
Figure 10: Gate Charge Characteristics

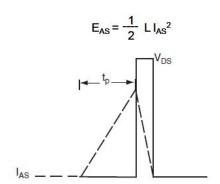


QG-Gate Charge (nC)

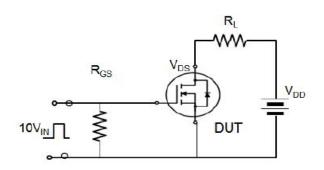


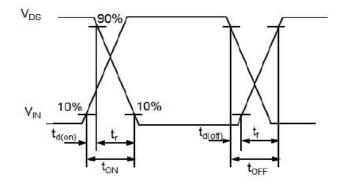
Avalanche Test Circuit



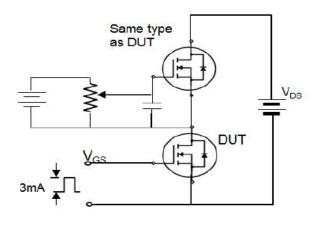


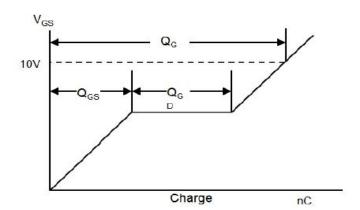
Switching Time Test Circuit





Gate Charge Test Circuit





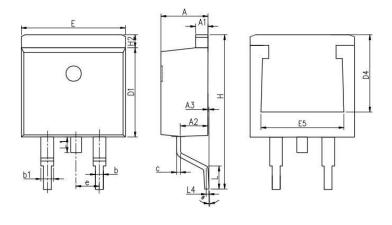


Device Per Unit

Package Type	Unit	Quantity
TO-263-2L	Reel	800

Package Information

TO-263-2L

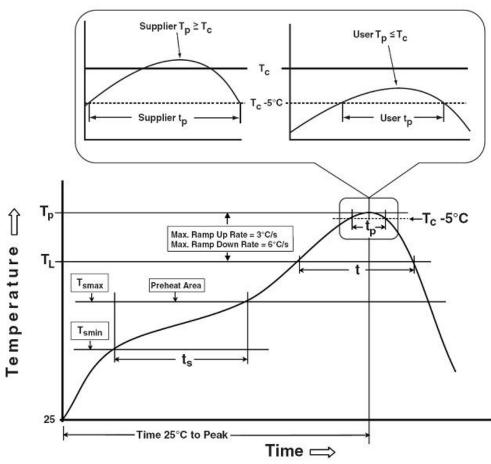


COMMON DIMENSIONS

	mm			
SYMBOL	MIN	NOM	MAX	
Α	4.37	4.57	4.77	
A1	1.22	1.27	1.42	
A2	2.49	2.69	2.89	
A3	0	0.13	0.25	
b	0.7	0.81	0.96	
b1	1.17	1.27	1.47	
С	0.3	0.38	0.53	
D1	8.5	8.7	8.9	
D4	6.6	-	-	
Е	9.86	10.16	10.36	
E5	7.06	-	ı	
е		2.54 BSC		
Н	14.7	15.1	15.5	
H2	1.07	1.27	1.47	
L	2	2.3	2.6	
L1	1.4	1.55	1.7	
L4	0.25 BSC			
θ	0°	5°	9°	



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly	
Preheat & Soak	100 °C	150 °C	
Temperature min (T _{smin})	150 °C	200 °C	
Temperature max (T _{smax})	60-120 seconds	60-120 seconds	
Time (Tsmin to Tsmax) (t₅)	00-120 Seconds	00-120 Seconds	
Average ramp-up rate	3 °C/sseard may	3°C/second max.	
(T _{smax} to T _P)	3 °C/second max.		
Liquidous temperature (T _L)	183 °C	217 °C	
Time at liquidous (t∟)	60-150 seconds	60-150 seconds	
Peak package body Temperature	See Classification Temp in table 1	SeeClassification Tempin table 2	
(T _p)*	See Classification Temp in table 1		
Time (t _P)** within 5°C of the specified	00**	20** accords	
classification temperature (Tc)	20** seconds	30** seconds	
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.	
Time 25°C to peak temperature	6 minutes max. 8 minutes max.		
*Tolerance for peak profile Temperature (T _p) is defined as a supplier minimum and a user maximum.			

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^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

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Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000Hrs, V _{gs} 100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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